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PATENT, TRADEMARK
AND COPYRIGHT LAW
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Date: December 15, 2000

Attorney Docket No. T&A-104

To: Assistant Commissioner for Patents
Washington, D.C. 20231

Sir: Transmitted herewith for filing is the patent application of:

Inventor: H. AOKI et al (SEE ATTACHED)

For:
METHOD OF TESTING MEMORY DEVICE, METHOD OF MANUFACTURING MEMORY
DEVICE, APPARATUS FOR TESTING MEMORY DEVICE, METHOD OF TESTING
MEMORY MODULE, METHOD OF MANUFACTURING MEMORY MODULE,
APPARATUS FOR TESTING MEMORY MODULE AND METHOD OF MANUFACTURING
COMPUTER

Enclosed are:

- ☒ 21 Sheets of Drawings
☐ This application is being filed without an executed Declaration.
☒ Priority is claimed from Japanese Application No. 11-358305
filed December 17, 1999 ☒ A certified copy is attached herewith.
Copies of the disclosure documents listed on the attached PTO 1449 form and
☒ discussed in the specification or ☒ attached Information Disclosure Statement.
☐ A verified statement to establish small entity status under 37 CFR 1.9 and 1.27.
☒ Specification: Abstract X, Description 44 pages; and 53 claim(s).
☐ Preliminary Amendment.
☒ Executed Declaration.

The filing fee is calculated as shown below:

For:	No. Filed	No. Extra
Basic Fee		
Total Claims	53 - 20 = *	33
Indep Claims	11 - 3 = *	8
<input type="checkbox"/> Multiple Dependent Claim (s)		

* If difference is less than zero
then enter '0' in second column

Small Entity

Rate	Fee
	\$ 355
x 9	\$
x 40	\$
+ 135	\$
Total	\$

Large Entity

Rate	Fee
	\$ 710
x 18	\$ 594
x 80	\$ 640
+ 270	\$ 0
Total	\$ 1,944

OR

☒ A check in the amount of \$ 1,944.00 is enclosed for the filing fee.

☒ The Commissioner is hereby authorized to charge any additional fees that may be required to
Deposit Account No. 50-1417.

Respectfully Submitted,

By: John R. Mattingly
Registration No. 30,293

United States Patent Application

Title of the Invention

METHOD OF TESTING MEMORY DEVICE, METHOD OF
MANUFACTURING MEMORY DEVICE, APPARATUS FOR TESTING
MEMORY DEVICE, METHOD OF TESTING MEMORY MODULE, METHOD
OF MANUFACTURING MEMORY MODULE, APPARATUS FOR TESTING
MEMORY MODULE AND METHOD OF MANUFACTURING COMPUTER

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